Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/719,484	CHEN ET AL.	
Examiner	Art Unit	
David E. Martinez	2181	

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East see attached	8/16/2006	DM 、		
Inventor Search eDan	8/16/2006	DM		
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